

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1363	SERIAL NO. 09/512,968	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micron Technology, Inc.		
				FILING DATE February 24, 2000	PRIORITY GROUP 2829	
U.S. PATENT DOCUMENTS						
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
VA	AA 5,703,287	12/1997	Treutler et al.			
	AB 5,945,834	8/1999	Nakata et al.			
	AC 5,478,242	12/1995	Walker et al.			
	AD 5,830,372	11/1998	Hierold			
	AE					
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)						
	AF					
	AG					
	AH					
	AI					
	AJ					
	AK					
	AL					
EXAMINER		DATE CONSIDERED				
<i>Mark Nguyen</i>		06/02/05				
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1363	SERIAL NO. 09/512,868			
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				FILING DATE February 24, 2000	PRIORITY GROUP 2029			
U.S. PATENT DOCUMENTS								
Examiner Initials		Document Number	Date	Name		Class	Subclass	Filing Date if Appropriate
VN	AA	6,635,852	10/21/2003	Salwa				
VN	AB	6,708,878	3/25/2004	Akram et al.				
VV	AC	6,645,701	11/11/2003	Ota et al.				
	AD							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AE							
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	AG							
	AH							
	AI							
	AJ							
	AK							
	AL							
EXAMINER				DATE CONSIDERED		06/02/05		
<u>mh Nguyen</u> <small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 808. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>								